

Product Name :
Scanning Electron Microscope**Product Code :**
EEMTL71M0003**Description :**

Scanning Electron Microscope

Technical Specification :

Description:

Scanning Electron

Characterization of surfaces of materials: - Easy Probe, a compact scanning electron microscope (SEM) fully integrated with a selected energy dispersive X-ray microanalyser (EDX).

Technical Specifications:

- Electron Gun: Tungsten heated cathode
- Magnification: 3x to 1,000,000x (for 5" image width in Continual Wide Field/Resolution)
- Maximum Field of View: 24 mm at WD 30 mm
- Accelerating Voltage: 200 V to 30 kV
- Probe Current: 1 pA to 2 μ A
- Scanning Speed: From 20 ns to 10 ms per pixel adjustable in steps or continuously

Scanning Features:

- Point & Line Scan, Focus Window – shape, size and position continuously adjustable, Dynamic Focus – in plane or folded plane tilted up to ± 70
- Deg, Image rotation, Image shift, Tilt compensation, 3D Beam –defined tilting scanning axis around XY axis, Live Stereoscopic Imaging, Other scanning shapes available through the Draw Beam software

Image File format:

- BMP, TIFF, JPEG (Selectable)

Control:

- Computer (PC) interface

Accessories:

- Computer, LCD Display



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